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 / Ruth Montalvo Date: 12/22/05

Customer No. 026418

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.: JG-SU-5222/500577.20072

U.S. Application No.:

International Application No.: PCT/JP2004/016001

International Filing Date: OCTOBER 28, 2004 28 OCTOBER 2004

Priority Date Claimed: DECEMBER 01, 2003 01 DECEMBER 2003

Title of Invention: MANUFACTURING METHOD OF SILICON WAFER

Applicant(s) for (DO/EO/US): Sakae KOYATA and Kazushige TAKAISHI

Mail Stop PCT  
Commissioner For Patents  
P.O. Box 1450  
Alexandria, VA 22313-450

## INFORMATION DISCLOSURE STATEMENT

S I R:

Applicant herewith submits together with the simultaneously filed National Phase application of PCT/JP2004/016001, a copy of the International Search Report (PCT/ISA/210) dated February 15, 2005, citing some of the following references:

	Document Number	Date	Name and/or Country	English Translation and/or Equivalent
AA	6,099,748	08/08/2000	Netsu, et al.	
AL	60-197367	10/05/1985	Japan	Abstract only
AM	07-045564	02/14/1995	Japan	Abstract only
AN	11-171693	06/29/1999	Japan	Abstract only
AO	11-233485	08/27/1999	Japan	Abstract only
AP	2001-223187	08/17/2001	Japan	Abstract only
AQ	2003-100701	04/04/2003	Japan	Abstract only
AR	2003-203890	08/17/2003	Japan	Abstract only

Accompanying this Information Disclosure Statement and form PTO-1449 are copies of the documents including English Abstract and US equivalent. Document A9 is mentioned on page 3 of the substitute specification.

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IA9 Rec'd PCT/PTO 22 DEC 2009

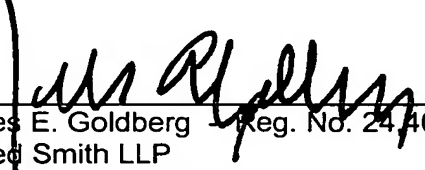
The USPTO waived the requirement under 37 C.F.R. §1.98(a)(2)(i) for submitting copies of US patents and US patent application publications in all U.S. applications filed after June 30, 2003. First pages of US documents only.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,

JEG:ram  
08/10/05  
Tel. (212) 521-5400  
Enclosures:

Search Report (PCT/ISA/210);  
PTO-1449  
1 first page US Patents  
7 foreign documents  
7 English Abstracts

  
\_\_\_\_\_  
Jules E. Goldberg Reg. No. 24,408  
Reed Smith LLP  
599 Lexington Avenue  
New York, NY 10022-7650

**LIST OF PRIOR ART CITED BY APPLICANT**  
(Filed on December 22, 2005)

Docket No. **JG-SU-5222/500577.20072**Applicant(s): **Sakae KOYATA and Kazushige TAKAISHI**

Application No. (Int'l Appln No. PCT/JP2004/016001 28OCT04) Group:

Filed: Examiner:

**U.S. PATENT DOCUMENTS**

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
	<b>AA</b>	<b>6,099,748</b>	<b>08/08/2000</b>	<b>Netsu, et al.</b>			
	<b>AB</b>						
	<b>AC</b>						
	<b>AD</b>						
	<b>AE</b>						
	<b>AF</b>						
	<b>AG</b>						
	<b>AH</b>						
	<b>AI</b>						
	<b>AJ</b>						
	<b>AK</b>						

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	CLASS	Sub-Class	Translation	
							YES	NO
	<b>AL</b>	<b>60-197367</b>	<b>10/05/1985</b>	<b>Japan</b>			Abstract only	
	<b>AM</b>	<b>07-045564</b>	<b>02/14/1995</b>	<b>Japan</b>			Abstract only	
	<b>AN</b>	<b>11-171693</b>	<b>06/29/1999</b>	<b>Japan</b>			Abstract only	
	<b>AO</b>	<b>11-233485</b>	<b>08/27/1999</b>	<b>Japan</b>			Abstract only	
	<b>AP</b>	<b>2001-223187</b>	<b>08/17/2001</b>	<b>Japan</b>			Abstract only	
	<b>AQ</b>	<b>2003-100701</b>	<b>04/04/2003</b>	<b>Japan</b>			Abstract only	
	<b>AR</b>	<b>2003-203890</b>	<b>08/17/2003</b>	<b>Japan</b>			Abstract only	
	<b>AS</b>							
	<b>AT</b>							

**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

	<b>AX</b>	
	<b>AY</b>	
	<b>AZ</b>	

Examiner:

Date:

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.